



JAPANESE
INDUSTRIAL
STANDARD

Translated and Published by
Japanese Standards Association

JIS C 5402-11-2 : 2005

(IEC 60512-11-2 : 2002)

(JEITA)

**Connectors for electronic equipment —
Tests and measurements — Part 11-2:
Climatic tests — Test 11b: Combined/
sequential cold, low air pressure and
damp heat**

ICS 31.220.10

Reference number : JIS C 5402-11-2 : 2005 (E)



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Foreword

This translation has been made based on the original Japanese Industrial Standard established by the Minister of Economy, Trade and Industry through deliberations at the Japanese Industrial Standards Committee according to the proposal of establishing a Japanese Industrial Standard from Japan Electronics and Information Technology Industries Association (JEITA) with a draft of Industrial Standard based on the provision of Article 12 Clause 1 of the Industrial Standardization Law.

This Standard has been made based on **IEC 60512-11-2:2002 Connectors for electronic equipment — Tests and measurements — Part 11-2: Climatic tests — Test 11b: Combined/sequential cold, low air pressure and damp heat** for the purposes of making it easier to compare this Standard with International Standard; to prepare Japanese Industrial Standard conforming with International Standard; and to propose a draft of an International Standard which is based on Japanese Industrial Standard. Attention is drawn to the possibility that some parts of this Standard may conflict with a patent right, application for a patent after opening to the public, utility model right or application for registration of utility model after opening to the public which have technical properties. The relevant Minister and the Japanese Industrial Standards Committee are not responsible for identifying the patent right, application for a patent after opening to the public, utility model right or application for registration of utility model after opening to the public which have the said technical properties.

JIS C 5402 series consists of the standards shown in **JIS C 5402-1-100**.

Date of Establishment: 2005-03-20

Date of Public Notice in Official Gazette: 2005-03-22

Investigated by: Japanese Industrial Standards Committee
Standards Board

Technical Committee on Electronics
Technology

JIS C 5402-11-2 :2005, First English edition published in 2005-06

Translated and published by: Japanese Standards Association
4-1-24, Akasaka, Minato-ku, Tokyo, 107-8440 JAPAN

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Printed in Japan

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